

Notice of References Cited	Application/Control No. 10/542,017		Applicant(s)/Patent Under Reexamination TAKEDA ET AL.	
	Examiner Sow-Fun Hon		Art Unit 1772	Page 1 of 1

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*	B	US-5,430,566	07-1995	Sakaya et al.	349/118
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.